

Search Notes



Application/Control No.

10/505,372

Examiner

Tan Ho

Applicant(s)/Patent under
Reexamination

MIYANO ET AL.

Art Unit

2821

SEARCHED

Class	Subclass	Date	Examiner
343	700NS	1/4/06	T.H.
	702		
	876		
	741		
	866		
✓	821	✓	✓
update searched above			
		5/12/06	T.H.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
West	1/8/06	T.H.